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| Notice of References Cited | Application/Control No. 10/800,586 | Applicant(s)/Patent Under Reexamination REED, DAVID L. | |
| | Examiner Brent A. Swarthout | Art Unit 2636 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | A | US-2001/0040501 | 11-2001 | RIGHT et al. | 340/331 |
| * | B | US-6,873,256 | 03-2005 | Lemelson et al. | 340/539.1 |
| * | C | US-4,531,114 | 07-1985 | Topol et al. | 340/539.1 |
| * | D | US-6,553,100 | 04-2003 | Chen et al. | 379/37 |
| * | E | US-4,893,324 | 01-1990 | Scown, Kenneth M. | 379/40 |
| * | F | US-3,969,720 | 07-1976 | Nishino, Shiro | 340/815.69 |
| * | G | US-6,693,534 | 02-2004 | Costa et al. | 340/531 |
| * | H | US-4,754,266 | 06-1988 | Shand et al. | 340/691.2 |
| * | I | US-6,646,545 | 11-2003 | Bligh, Maurice | 340/286.05 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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